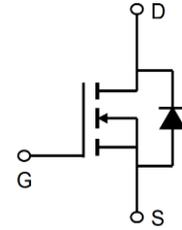


100V N-Channel Enhancement Mode MOSFET

Description

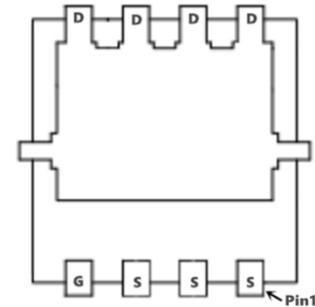
The AP120N10NF uses advanced **APM-SGT I I** technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.



General Features

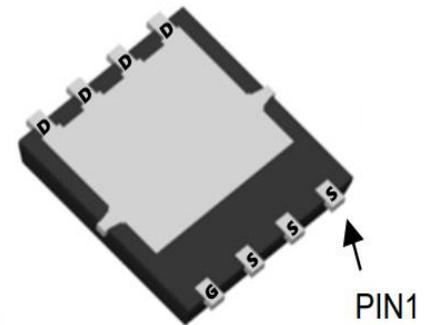
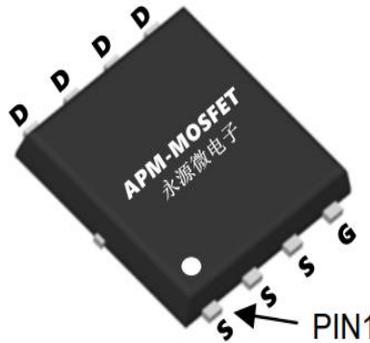
$V_{DS} = 100V$ $I_D = 120A$

$R_{DS(ON)} < 4.5m\Omega$ @ $V_{GS}=10V$ (Type: **3.8mΩ**)



Application

- Isolated DC
- Motor control
- Synchronous-rectification



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP120N10NF	PDFN5*6-8L	AP120N10NF XXX YYYY	5000

Absolute Maximum Ratings ($T_C=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	100	V
V _{GS}	Gate-Source Voltage	±20	V
I _D @T _A =25°C	Continuous Drain Current ¹	120	A
I _D @T _A =70°C	Continuous Drain Current ¹	76	A
IDM	Pulsed Drain Current ²	480	A
EAS	Single Pulse Avalanche Energy ³	320	mJ
IAS	Avalanche Current	40	A
P _D @T _A =25°C	Total Power Dissipation ⁴	131.6	W
TSTG	Storage Temperature Range	-55 to 150	°C
T _J	Operating Junction Temperature Range	-55 to 150	°C
R _{θJA}	Thermal Resistance Junction-Ambient ¹	25	°C/W
R _{θJC}	Thermal Resistance Junction-Case ¹	0.95	°C/W

100V N-Channel Enhancement Mode MOSFET

Electrical Characteristics ($T_C=25^{\circ}\text{C}$ unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu A$	100	107	-	V
IGSS	Gate-body Leakage current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	± 100	nA
IDSS	Zero Gate Voltage Drain Current $T_J=25^{\circ}\text{C}$	$V_{DS}=100V, V_{GS}=0V$	-	-	1	μA
	Zero Gate Voltage Drain Current $T_J=100^{\circ}\text{C}$		-	-	100	
VGS(th)	Gate-Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	2.0	3.0	4.0	V
RDS(on)	Drain-Source on-Resistance ⁴	$V_{GS} = 10V, I_D = 20A$	-	3.8	4.5	m Ω
gfs	Forward Transconductance ⁴	$V_{DS} = 10V, I_D = 20A$	-	62	-	S
Ciss	Input Capacitance	$V_{DS} = 50V, V_{GS} = 0V, f = 1\text{MHz}$	-	6865	-	pF
Coss	Output Capacitance		-	740	-	
Crss	Reverse Transfer Capacitance		-	21	-	
Rg	Gate Resistance	$f = 1\text{MHz}$	-	1.3	-	Ω
Qg	Total Gate Charge	$V_{GS} = 10V, V_{DS} = 50V, I_D = 20A$	-	111.2	-	nC
Qgs	Gate-Source Charge		-	30.5	-	
Qgd	Gate-Drain Charge		-	27.3	-	
td(on)	Turn-on Delay Time	$V_{GS} = 10V, V_{DD} = 50V, R_G = 3\Omega, I_D = 20A$	-	33	-	ns
tr	Rise Time		-	39	-	
td(off)	Turn-off Delay Time		-	67.1	-	
tf	Fall Time		-	32	-	
trr	Body Diode Reverse Recovery Time	$I_F = 20A, dI/dt = 100A/\mu s$	-	58.7	-	ns
Qrr	Body Diode Reverse Recovery Charge		-	97.3	-	nC
VSD	Diode Forward Voltage ⁴	$I_S = 20A, V_{GS} = 0V$	-	-	1.2	V
IS	Continuous Source Current $T_C=25^{\circ}\text{C}$	-	-	-	120	A

Note :

- 1、 The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- 2、 The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
- 3、 The EAS data shows Max. rating . The test condition is $V_{DD}=72V, V_{GS}=10V, L=0.1\text{mH}$ $I_{AS}=40A$
- 4、 The power dissipation is limited by 150°C junction temperature
- 5、 The data is theoretically the same as I D and I DM , in real applications , should be limited by total power dissipation

Typical Characteristics

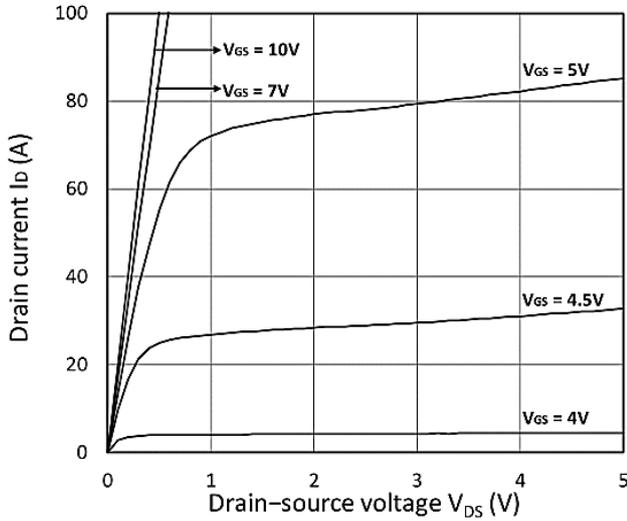


Figure 1. Output Characteristics

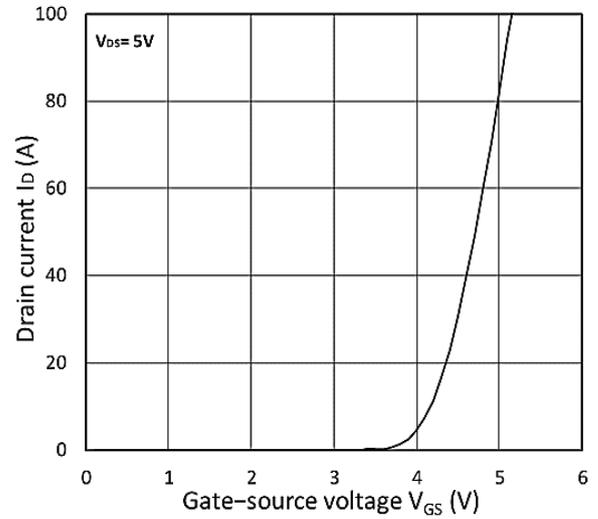


Figure 2. Transfer Characteristics

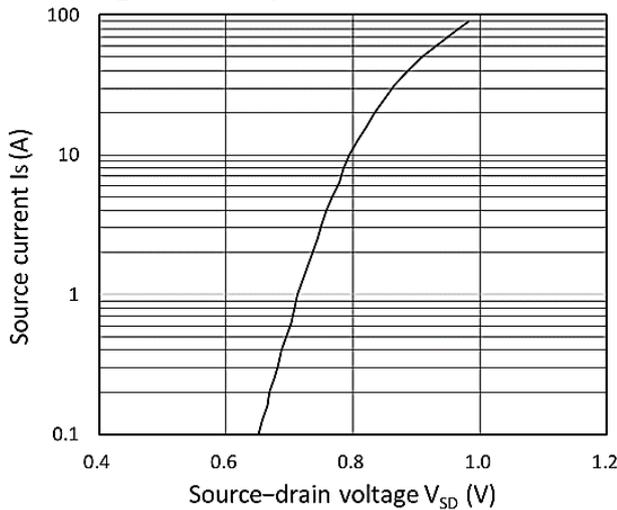


Figure 3. Forward Characteristics of Reverse

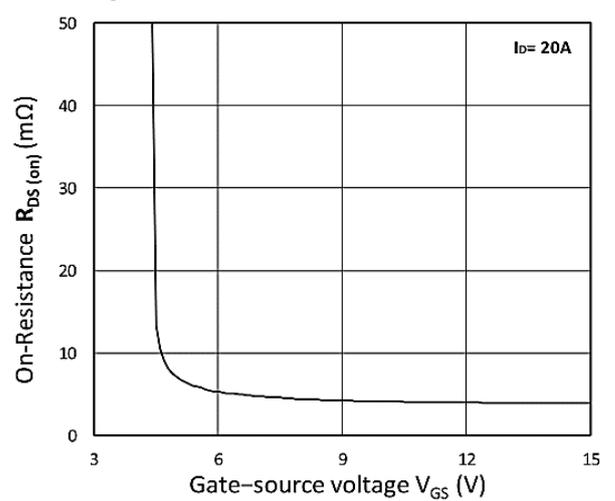


Figure 4. RDS(ON) vs. VGS

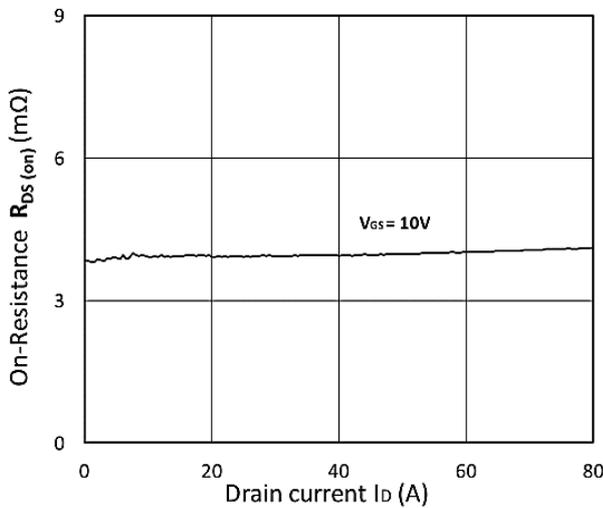


Figure 5. RDS(ON) vs. ID

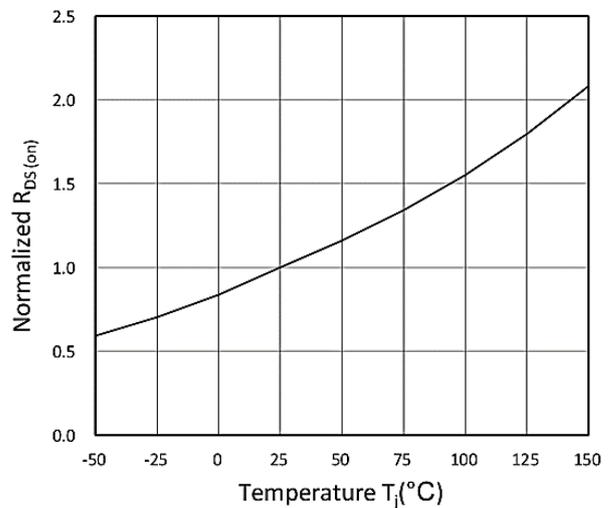


Figure 6. Normalized RDS(on) vs. Temperature



100V N-Channel Enhancement Mode MOSFET

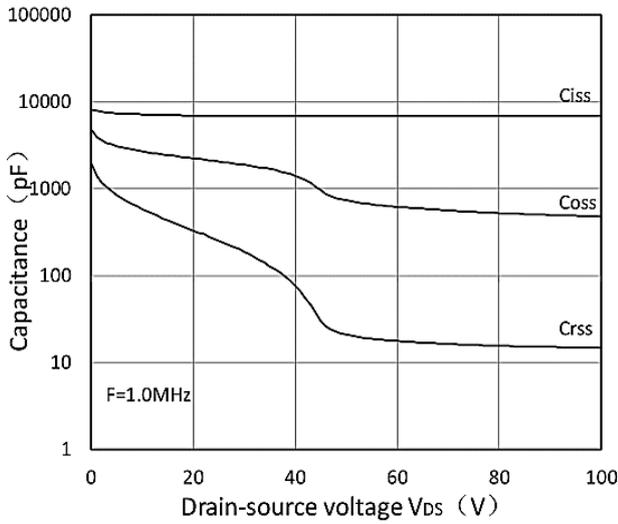


Figure 7. Capacitance Characteristics

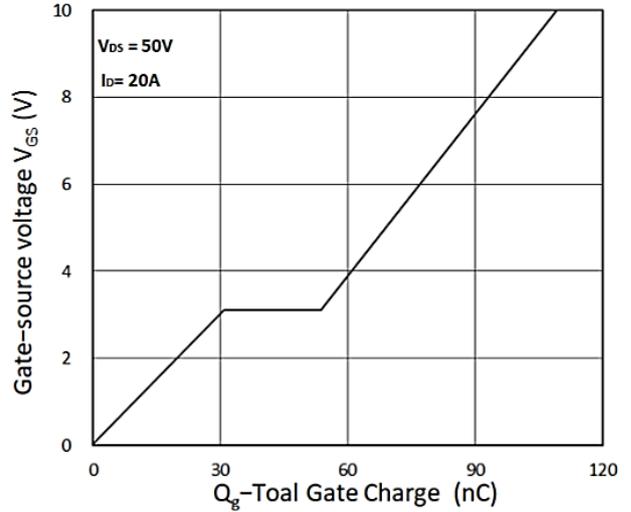


Figure 8. Gate Charge Characteristics

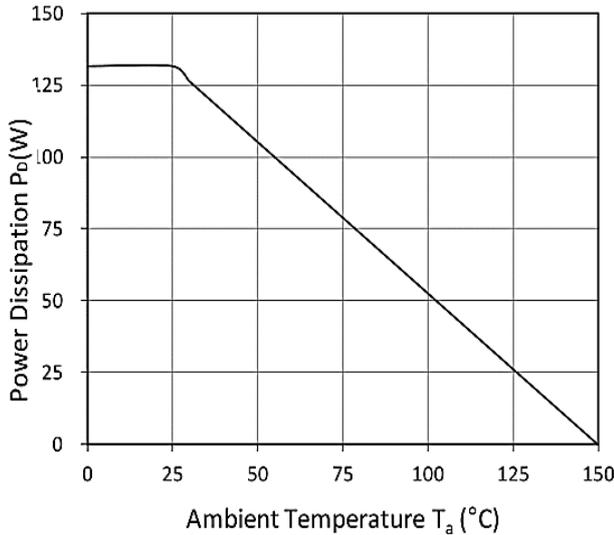


Figure 9. Power Dissipation

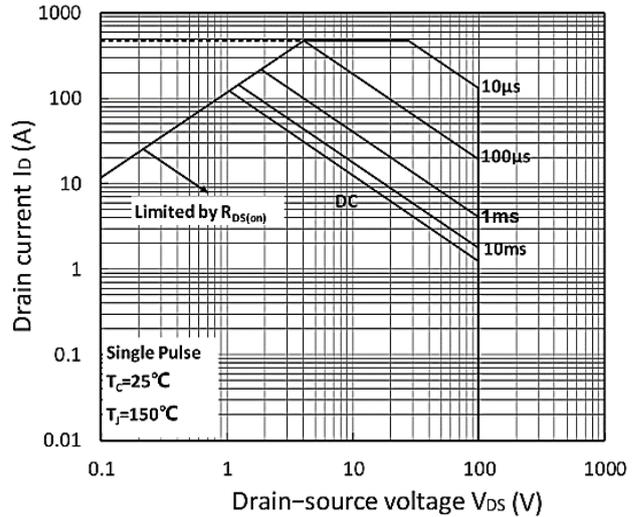


Figure 10. Safe Operating Area

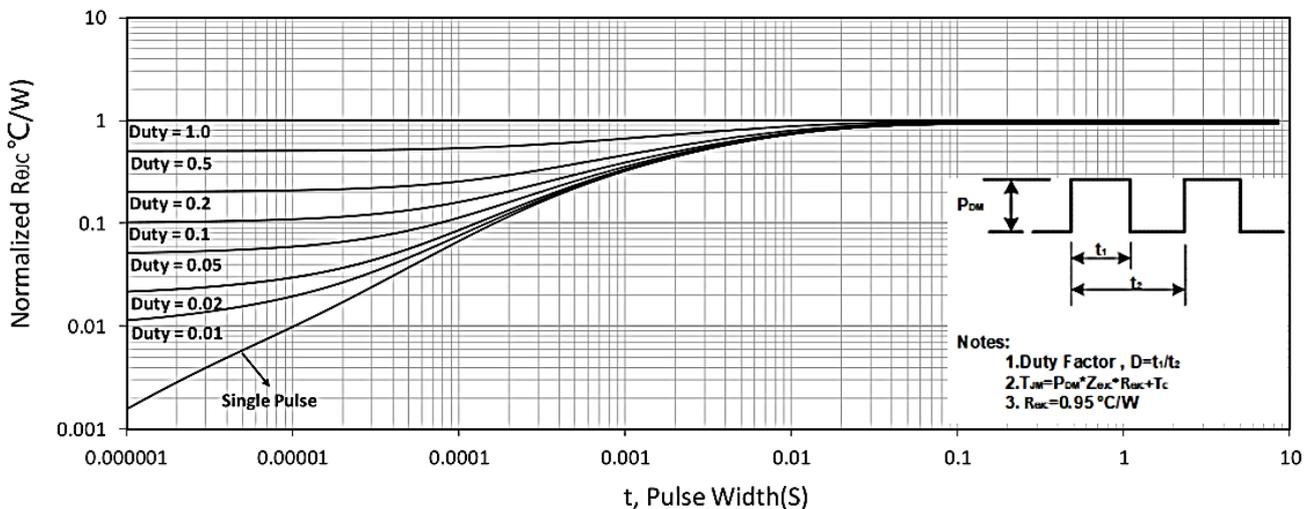
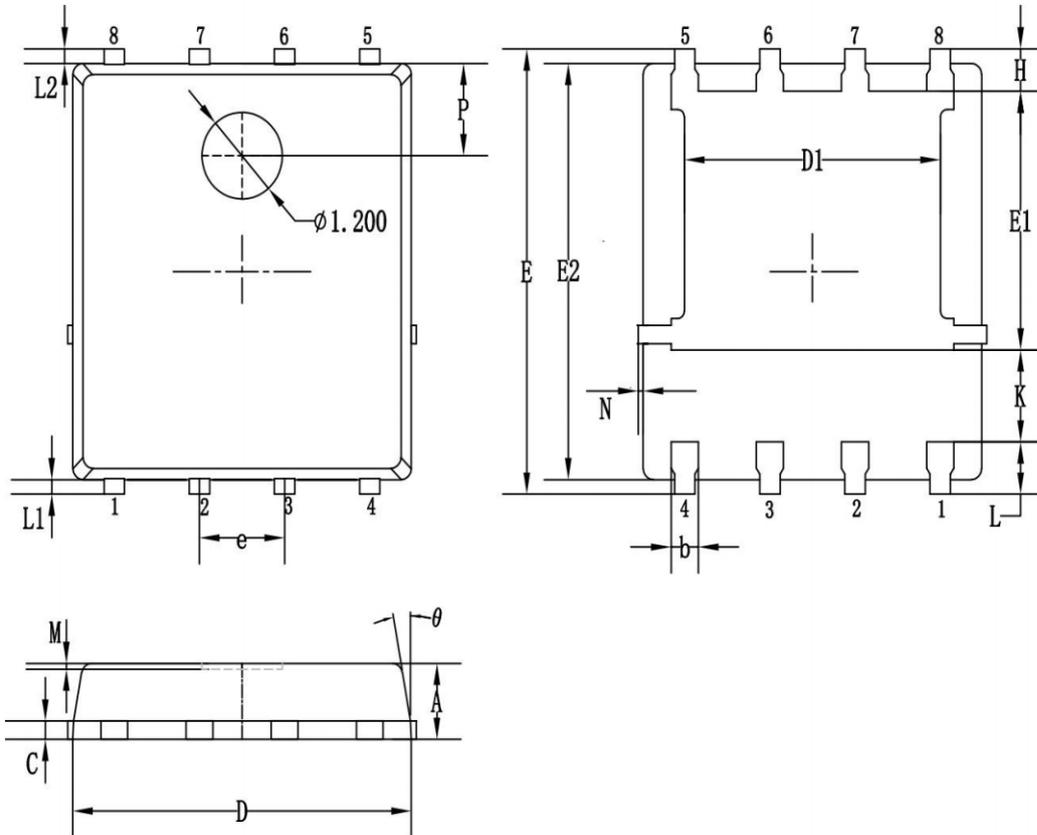


Figure 11. Normalized Maximum Transient Thermal Impedance

Package Mechanical Data-PDFN5X6-8L Single



Symbol	Dim in mm		
	min.	typ.	max.
A	0.9	1.05	1.2
b	0.3	0.4	0.5
C	0.2	0.25	0.35
D	4.9	5.05	5.2
D1	3.72	3.82	4.12
E	5.9	6.1	6.3
E1	3.3	3.5	3.7
E2	5.6	5.75	5.9
e	1.27BSC		
H	0.48	0.58	0.7
K	1.14	1.27	1.4
L	0.54	0.74	0.84
L1/L2	0.1	0.2	0.3
θ	8°	10°	12°
M	0.08REF		
N	0		0.15
P	1.28REF		

100V N-Channel Enhancement Mode MOSFET**Attention**

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Edition	Date	Change
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Rve1.1	2025/1/6	Update LOGO And POD

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